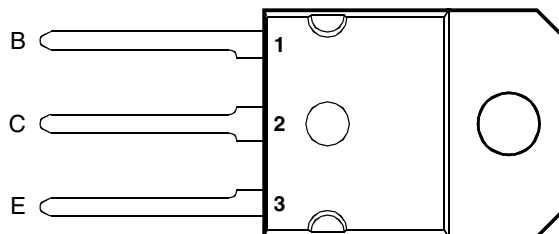


**BOURNS®**

- Rugged Triple-Diffused Planar Construction
- 9 A Continuous Collector Current
- 1000 Volt Blocking Capability

**SOT-93 PACKAGE**  
**(TOP VIEW)**


Pin 2 is in electrical contact with the mounting base.

MDTRAAA

**absolute maximum ratings at 25°C case temperature (unless otherwise noted)**

RATING		SYMBOL	VALUE	UNIT
Collector-emitter voltage ( $V_{BE} = -2.5$ V)	BUV47	$V_{CEX}$	850	V
	BUV47A		1000	
Collector-emitter voltage ( $R_{BE} = 10 \Omega$ )	BUV47	$V_{CER}$	850	V
	BUV47A		1000	
Collector-emitter voltage ( $I_B = 0$ )	BUV47	$V_{CEO}$	400	V
	BUV47A		450	
Continuous collector current		$I_C$	9	A
Peak collector current (see Note 1)		$I_{CM}$	15	A
Continuous base current		$I_B$	3	A
Peak base current		$I_{BM}$	6	A
Continuous device dissipation at (or below) 25°C case temperature		$P_{tot}$	120	W
Operating junction temperature range		$T_j$	-65 to +150	°C
Storage temperature range		$T_{stg}$	-65 to +150	°C

 NOTE 1: This value applies for  $t_p \leq 5$  ms, duty cycle  $\leq 2\%$ .

**PRODUCT INFORMATION**

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# BUV47, BUV47A

## NPN SILICON POWER TRANSISTORS

**BOURNS®**

### electrical characteristics at 25°C case temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS			MIN	TYP	MAX	UNIT
$V_{CE(sus)}$ Collector-emitter sustaining voltage	$I_C = 200 \text{ mA}$	$L = 25 \text{ mH}$	(see Note 2)	BUV47 400			V
$V_{(BR)EBO}$ Base-emitter breakdown voltage	$I_E = 50 \text{ mA}$	$I_C = 0$	(see Note 3)			30	V
$I_{CES}$ Collector-emitter cut-off current	$V_{CE} = 850 \text{ V}$	$V_{BE} = 0$		BUV47		0.15	mA
	$V_{CE} = 1000 \text{ V}$	$V_{BE} = 0$		BUV47A		0.15	
	$V_{CE} = 850 \text{ V}$	$V_{BE} = 0$	$T_C = 125^\circ\text{C}$	BUV47		1.5	
	$V_{CE} = 1000 \text{ V}$	$V_{BE} = 0$	$T_C = 125^\circ\text{C}$	BUV47A		1.5	
$I_{CER}$ Collector-emitter cut-off current	$V_{CE} = 850 \text{ V}$	$R_{BE} = 10 \Omega$		BUV47		0.4	mA
	$V_{CE} = 1000 \text{ V}$	$R_{BE} = 10 \Omega$		BUV47A		0.4	
	$V_{CE} = 850 \text{ V}$	$R_{BE} = 10 \Omega$	$T_C = 125^\circ\text{C}$	BUV47		3.0	
	$V_{CE} = 1000 \text{ V}$	$R_{BE} = 10 \Omega$	$T_C = 125^\circ\text{C}$	BUV47A		3.0	
$I_{EBO}$ Emitter cut-off current	$V_{EB} = 5 \text{ V}$	$I_C = 0$				1	mA
$V_{CE(sat)}$ Collector-emitter saturation voltage	$I_B = 1 \text{ A}$	$I_C = 5 \text{ A}$	(see Notes 3 and 4)			1.5	V
	$I_B = 2.5 \text{ A}$	$I_C = 8 \text{ A}$				3.0	
$V_{BE(sat)}$ Base-emitter saturation voltage	$I_B = 1 \text{ A}$	$I_C = 5 \text{ A}$	(see Notes 3 and 4)			1.6	V
$f_t$ Current gain bandwidth product	$V_{CE} = 10 \text{ V}$	$I_C = 0.5 \text{ A}$	$f = 1 \text{ MHz}$		8		MHz
$C_{ob}$ Output capacitance	$V_{CB} = 20 \text{ V}$	$I_C = 0$	$f = 0.1 \text{ MHz}$		105		pF

NOTES: 2. Inductive loop switching measurement.

3. These parameters must be measured using pulse techniques,  $t_p = 300 \mu\text{s}$ , duty cycle  $\leq 2\%$ .

4. These parameters must be measured using voltage-sensing contacts, separate from the current carrying contacts.

### thermal characteristics

PARAMETER	MIN	TYP	MAX	UNIT
$R_{\theta JC}$ Junction to case thermal resistance			1	$^\circ\text{C/W}$

### resistive-load-switching characteristics at 25°C case temperature

PARAMETER	TEST CONDITIONS †			MIN	TYP	MAX	UNIT
$t_{on}$ Turn on time	$I_C = 5 \text{ A}$	$I_{B(on)} = 1 \text{ A}$	$I_{B(off)} = -1 \text{ A}$			1.0	$\mu\text{s}$
$t_s$ Storage time						3.0	$\mu\text{s}$
$t_f$ Fall time						0.8	$\mu\text{s}$

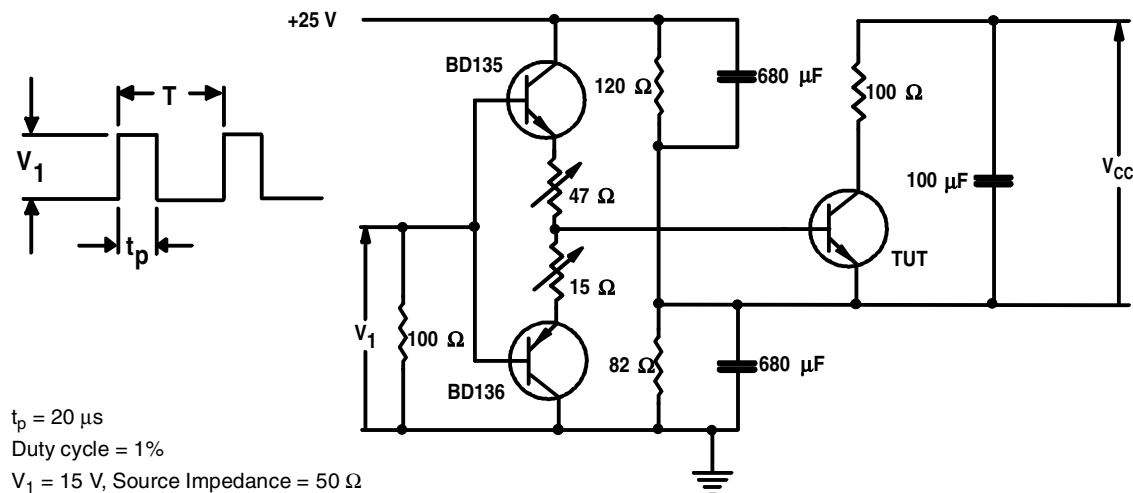
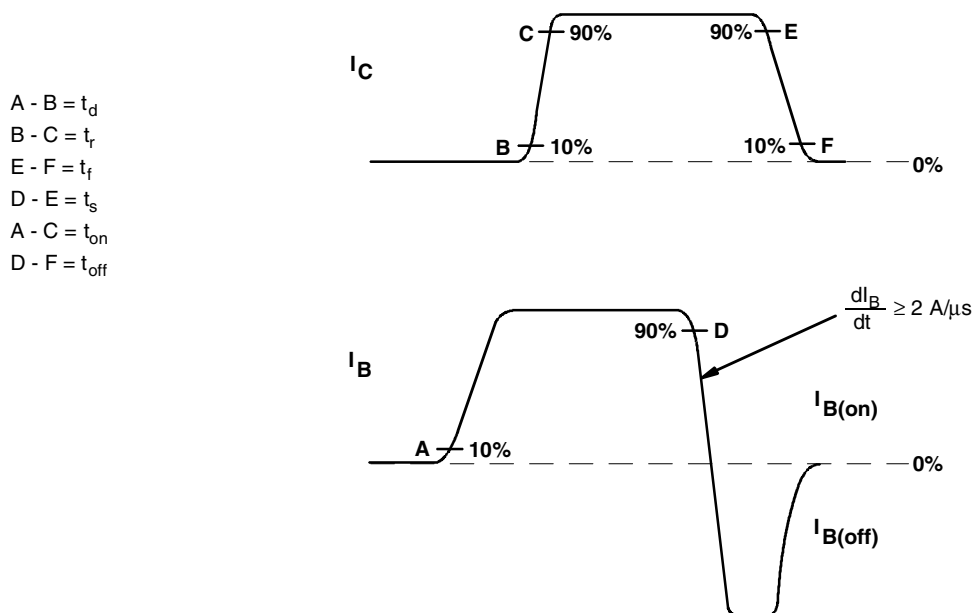
† Voltage and current values shown are nominal; exact values vary slightly with transistor parameters.

### inductive-load-switching characteristics at 25°C case temperature (unless otherwise noted)

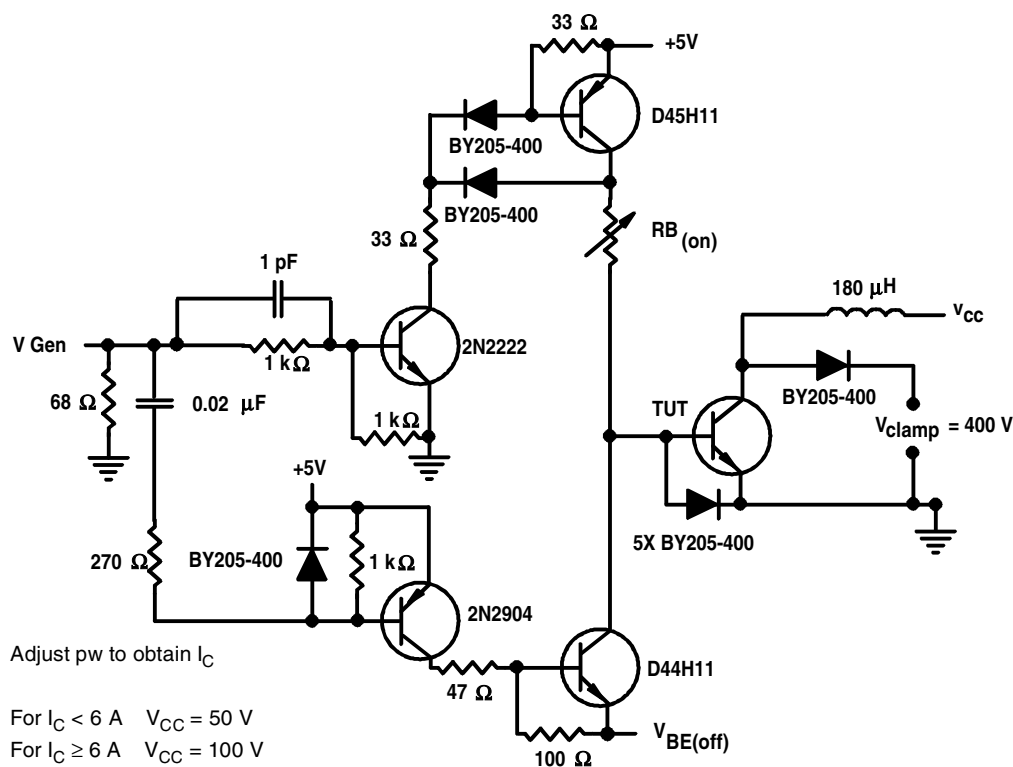
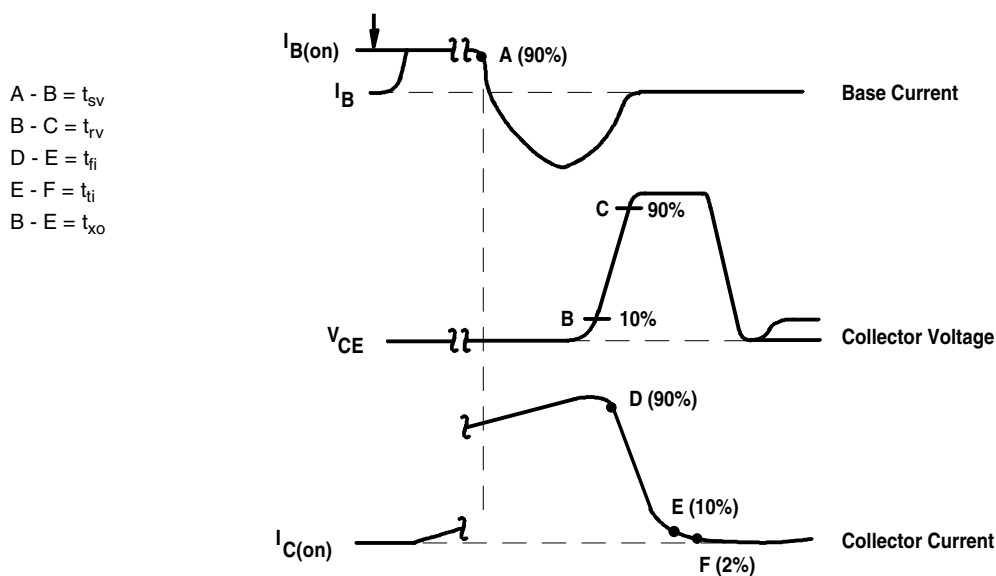
PARAMETER	TEST CONDITIONS †			MIN	TYP	MAX	UNIT
$t_{sv}$ Voltage storage time	$I_C = 5 \text{ A}$	$I_{B(on)} = 1 \text{ A}$	$V_{BE(off)} = -5 \text{ V}$			4.0	$\mu\text{s}$
$t_{fi}$ Current fall time	$T_C = 100^\circ\text{C}$	(see Figures 3 and 4)				0.4	$\mu\text{s}$

**PRODUCT INFORMATION**

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**PARAMETER MEASUREMENT INFORMATION**

**Figure 1. Resistive-Load Switching Test Circuit**

**Figure 2. Resistive-Load Switching Waveforms**
**PRODUCT INFORMATION**

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**PARAMETER MEASUREMENT INFORMATION**

**Figure 3. Inductive-Load Switching Test Circuit**


NOTES: A. Waveforms are monitored on an oscilloscope with the following characteristics:  $t_r < 15 \text{ ns}$ ,  $R_{in} > 10 \Omega$ ,  $C_{in} < 11.5 \text{ pF}$ .  
 B. Resistors must be noninductive types.

**Figure 4. Inductive-Load Switching Waveforms**



TYPICAL CHARACTERISTICS

TYPICAL DC CURRENT GAIN  
VS  
COLLECTOR CURRENT

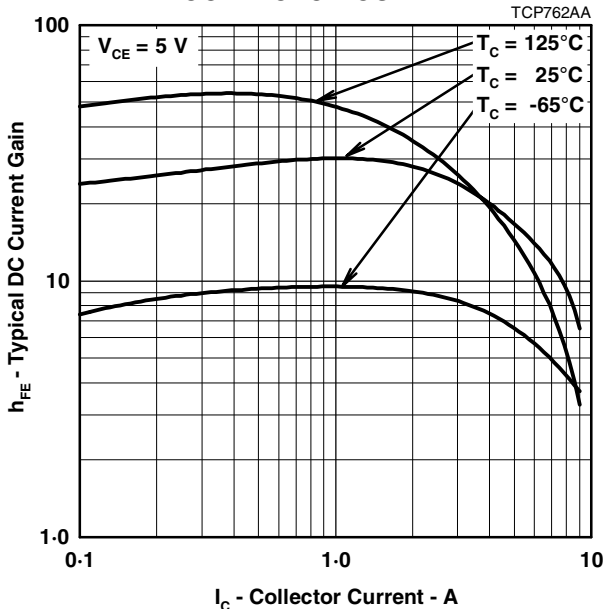


Figure 5.

COLLECTOR-EMITTER SATURATION VOLTAGE  
VS  
BASE CURRENT

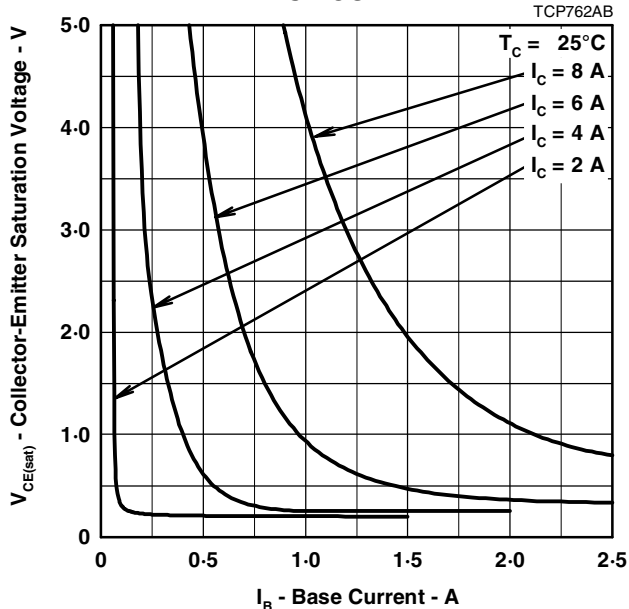


Figure 6.

COLLECTOR-EMITTER SATURATION VOLTAGE  
VS  
BASE CURRENT

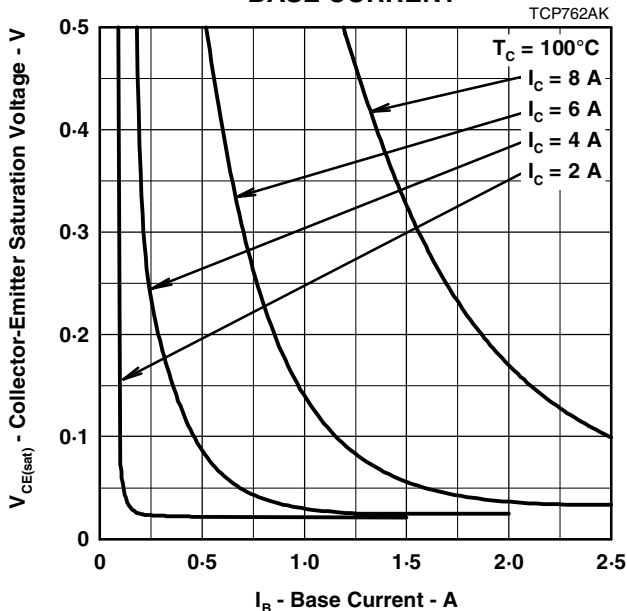


Figure 7.

COLLECTOR CUT-OFF CURRENT  
VS  
CASE TEMPERATURE

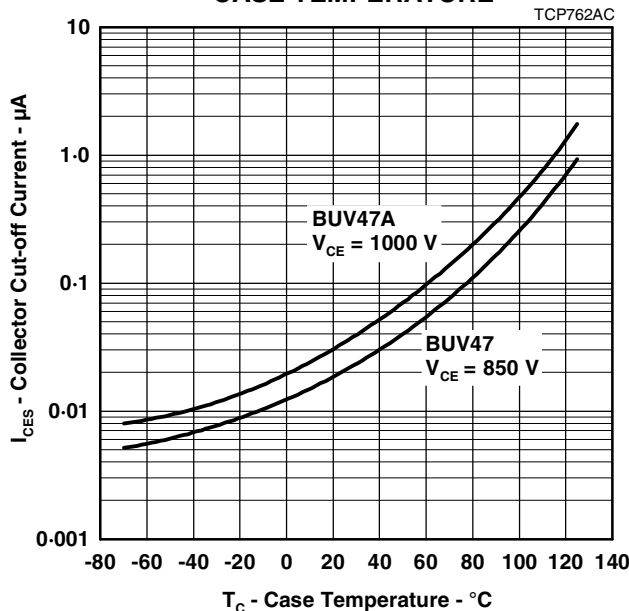


Figure 8.

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**MAXIMUM SAFE OPERATING REGIONS**

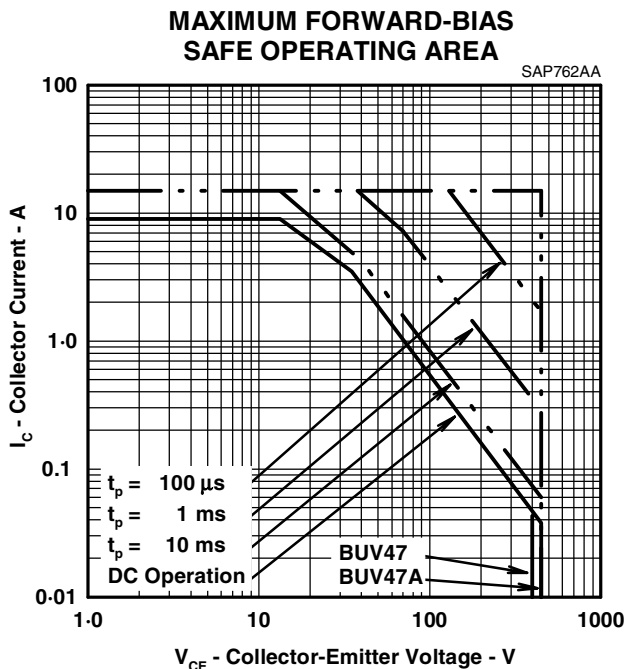


Figure 9.

**THERMAL INFORMATION**

**THERMAL RESPONSE JUNCTION TO CASE  
VS  
POWER PULSE DURATION**

TCP762AD

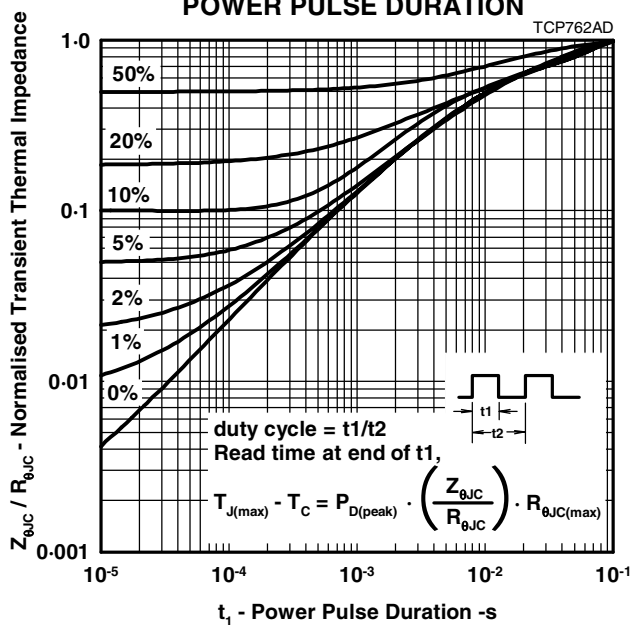
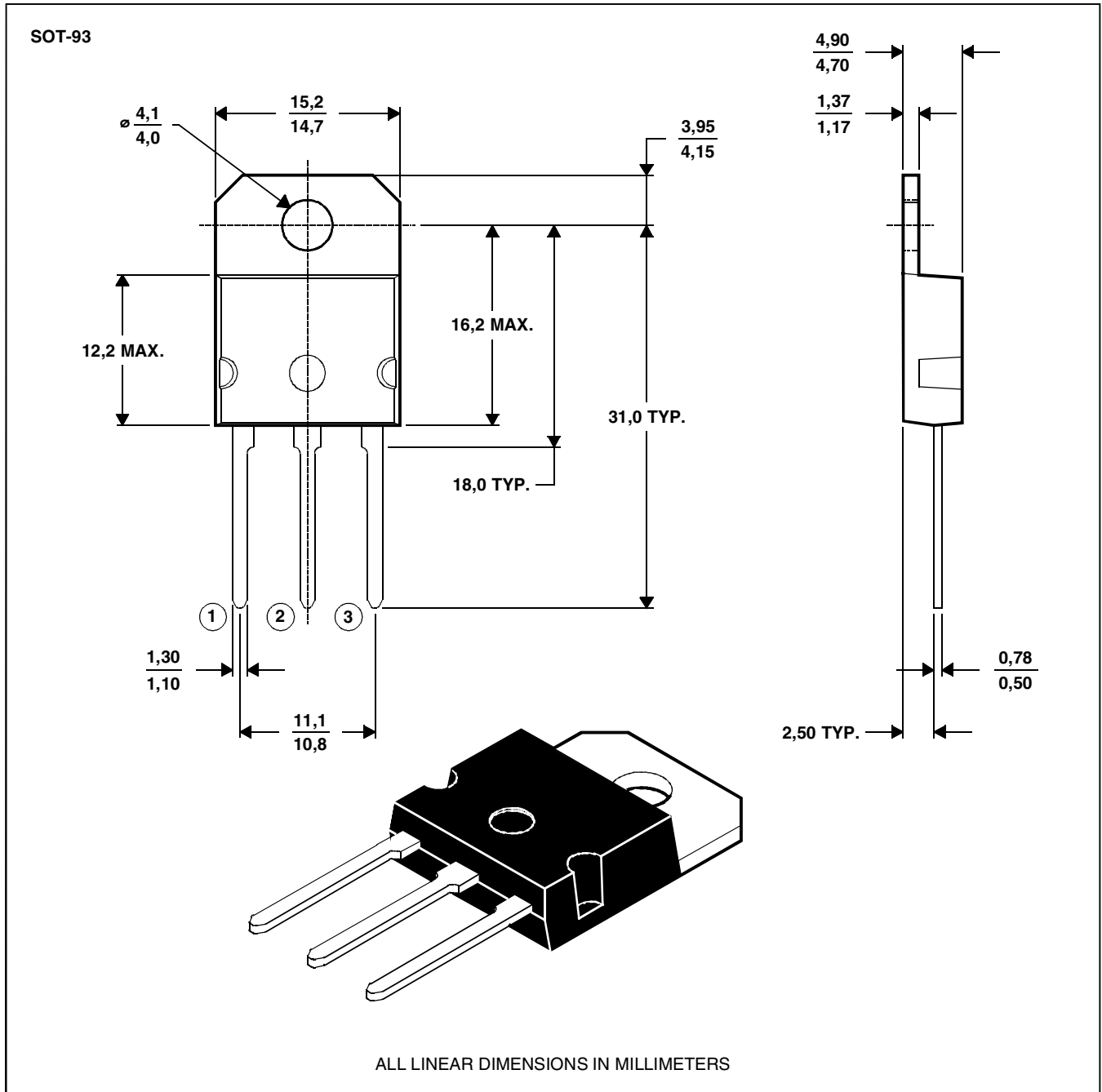


Figure 10.

**BOURNS®**
**MECHANICAL DATA**
**SOT-93**
**3-pin plastic flange-mount package**

This single-in-line package consists of a circuit mounted on a lead frame and encapsulated within a plastic compound. The compound will withstand soldering temperature with no deformation, and circuit performance characteristics will remain stable when operated in high humidity conditions. Leads require no additional cleaning or processing when used in soldered assembly.



NOTE A: The centre pin is in electrical contact with the mounting tab.

MDXXAW

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